	Application No.	Applicant(s)	
Notice of Allowability	09/757,955	LEONARD ET AL.	
	Examiner	Art Unit	
	William P. Fletcher III	1762	,
Th MAILING DATE of this communication apperall claims being allowable, PROSECUTION ON THE MERITS IS nerewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RID of the Office or upon petition by the applicant. See 37 CFR 1.313	(OR REMAINS) CLOSED in this app or other appropriate communication GHTS. This application is subject to	olication. If not included will be mailed in due course. Th	HIS itiative
 1. ☐ This communication is responsive to the response filed 11/2. 2. ☐ The allowed claim(s) is/are 1-62. 3. ☐ The drawings filed on 10 January 2001 are accepted by the 4. ☐ Acknowledgment is made of a claim for foreign priority una) ☐ All b) ☐ Some* c) ☐ None of the: 	e Examiner. nder 35 U.S.C. § 119(a)-(d) or (f).		
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International Bureau (PCT Rule 17.2(a)).	cuments have been received in this i	lational stage application from t	110
* Certified copies not received:		•	
 Acknowledgment is made of a claim for domestic priority un reference was included in the first sentence of the specifical 	ation or in an Application Data Sheet		С
 (a) The translation of the foreign language provisional a Acknowledgment is made of a claim for domestic priority upon the first sentence of the specification or in an Application 	nder 35 U.S.C. §§ 120 and/or 121 si	nce a specific reference was inc	luded
Applicant has THREE MONTHS FROM THE "MAILING DATE" of below. Failure to timely comply will result in ABANDONMENT of	f this communication to file a reply co	omplying with the requirements r	noted ABLE
 A SUBSTITUTE OATH OR DECLARATION must be subm INFORMAL PATENT APPLICATION (PTO-152) which give 	itted. Note the attached EXAMINER es reason(s) why the oath or declara	S AMENDMENT or NOTICE Of tion is deficient.	F
 CORRECTED DRAWINGS (as "replacement sheets") mus (a) ☐ including changes required by the Notice of Draftspers 1) ☐ hereto or 2) ☐ to Paper No 		948) attached	
(b) ☐ including changes required by the proposed drawing of	correction filed, which has be	en approved by the Examiner.	
(c) including changes required by the attached Examiner's			
Identifying indicia such as the application number (see 37 CFR 1 each sheet. Replacement sheet(s) should be labeled as such in t	.84(c)) should be written on the drawing the margin according to 37 CFR 1.121(ngs in the front (not the back) of d).	
 DEPOSIT OF and/or INFORMATION about the depo attached Examiner's comment regarding REQUIREMENT FOR T 	sit of BIOLOGICAL MATERIAL r THE DEPOSIT OF BIOLOGICAL MA	nust be submitted. Note the TERIAL.	
Attachment(s)			
1☐ Notice of References Cited (PTO-892)		tent Application (PTO-152)	
 2☐ Notice of Draftperson's Patent Drawing Review (PTO-948) 3☑ Information Disclosure Statements (PTO-1449 or PTO/SB/08 Paper No. <u>various</u> 	•	PTO-413), Paper No	
	^{3),} 7⊠ Examiner's Amendm	ent/Comment	
4☐ Examiner's Comment Regarding Requirement for Deposit of Biological Material	8⊠ Examiner's Statemer 9⊡ Other .	wit of Reasons for Allowance UPF 1/21/63 William Phillip Fletcher III Patent Examiner, USPTO Group Art Unit 1762	

EXAMINER'S AMENDMENT

1. An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

Authorization for this examiner's amendment was given in a telephone interview with David R. Cleveland (Reg. No. 29,524) on 11/21/03.

The application has been amended as follows:

In the claims...

...non-elected claims 63 – 80 have been cancelled.

...claim 1 has been amended to read:

- 1. (twice amended) A method for improving the uniformity of a wet coating on a substrate having a direction of motion comprising contacting the wet coating at a first position with wetted surface portions of:
 - a) two or more pick-and-place devices that rotate or translate in the direction of motion, or
 - b) four or more pick-and-place devices that rotate or translate counter to the direction of motion

and re-contacting the wet coating with such wetted surface portions at positions on the substrate whose lengths along the substrate with respect to the first position are not the same.

...claim 13 has been amended to read:

- 13. (twice amended) A method for improving the uniformity of a wet coating on a substrate comprising contacting the coating at a first position with wetted surface portions of:
 - a) three or more periodic pick-and-place devices that are not periodically related, or
 - b) two or more rotating periodic pick-and-place devices having the same direction of rotation

and re-contacting the coating with such wetted surface portions at positions on the substrate that are different from the first position and not periodically related to one another with respect to their distance from the first position, wherein at least one of the pick-and-place devices comprises a roll and there is a sinusoidal speed differential between the substrate and [at least one roll] two or more rolls.

...claim 23 has been amended to read:

- 23. (twice amended) A method for applying a coating to a substrate having a direction of motion comprising deliberately applying to the substrate an uneven wet coating, contacting the wet coating at a first position with wetted surface portions of:
 - a) two or more pick-and-place devices that rotate or translate in the direction of motion, or

b) four or more pick-and-place devices that rotate or translate counter to the direction of motion

and re-contacting the wet coating with such wetted surface portions at positions on the substrate whose lengths along the substrate with respect to the first position are not the same.

- 2. Claims 1 62 are allowed.
- 3. The following is an examiner's statement of reasons for allowance:

The reasons for allowance of claims 6, 7, 12 - 16, 18 - 22, 31, 42, 45 - 48, and 58 are set-forth at pp. 10 - 11 of the Office action mailed 10/10/03.

Applicant's arguments, see the response, filed 11/04/03, with respect to the objections and rejections under 35 U.S.C. 112, 2nd Paragraph, have been fully considered and are persuasive. These objections and rejections have been withdrawn.

With respect to claims 1 and 23, Reade neither teaches nor suggests the use of four or more pick-and-place devices. Further, the rollers of Hall do not re-contact at lengths along the substrate with respect to the first position that are not the same. Rather, the method of Hall recontacts at the same lengths, with the transverse movement of the rollers smoothing out the imperfections transmitted down the length of the substrate [see p. 2, ll. 18 – 37 of Hall]. Consequently, the prior art neither teaches nor suggests a method employing the pick-and-place devices claimed.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue

fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to William P. Fletcher III whose telephone number is (703) 308-7956. The examiner can normally be reached on Monday through Friday, 9 AM to 5 PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Shrive P. Beck can be reached on (703) 308-2333. The fax phone number for the organization where this application or proceeding is assigned is (703) 872-9310.

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is (703) 308-0661.

William P. Fletcher III

Examiner Art Unit 1762

SHRIVE P. MECK
SUPERVISORY PATENT EXAMINER
TECHNOLOGY CENTER 1700